L Number	Hits	Search Text	DB	Time stamp
1	3	365/189.09,189.11,230.06,201,226,190,203-205 and (bias with generator) same SRAM same test$3	US-PAT;154,15 US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:33
2	22	365/189.09,189.11,230.06,201,226,190,203-205 and (bias with generator) same SRAM	US-PAT;154,15 US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:35
3	20	(adjust$3 with bias) same (test with memory)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:36
4	4	365/201.ccls. and (adjust$3 with bias) same (test with memory)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:37
5	96	365/$.ccls. and (((pull-up or pull-down) with transistor) or (metal with program$4)) and (adjust$4 or level$) and bias same voltage same test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:39
6	56	365/189.09,189.11,230.06,201,226,190,203-205 and (((pull-up or pull-down) with transistor) or (metal with program$4)) and (adjust$4 or level$) and bias same voltage same test$4 and (SRAM or (static	US-PAT;154,15 US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:39
7	29	365/189.09,189.11,230.06,201,226,190,203-205 and (((pull-up or pull-down) with transistor) or (metal with program$4)) and (adjust$4 or level$) same bias same voltage same test$4 and (SRAM or (static	US-PAT;154,15 US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:39
-	6	with random with access memory)) and (voltage with output with signal) and (metal with program$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:32
-	14	(bias with generator) and SRAM and voltage same output same signal and (metal with program$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 16:12
-	1	((Blaine with Stackhouse) and (Hewlett with packard with development with company))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 16:20
-	4	((Blaine with Stackhouse) or (Hewlett with packard with development with company)) and (bias with generator)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 16:22
-	103	((Blaine with Stackhouse) or (Hewlett with packard with development with company)) and 365/$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 16:22
-	27	((Blaine with Stackhouse) or (Hewlett with packard with development with company)) and 365/$.ccls. and bias	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 16:55

-	10	((Blaine with Stackhouse) or (Hewlett with packard with development with company)) and 365/$.ccls. and bias and metal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 16:24	
-	3	365/$.ccls. and (bias with generator) same transistor same metal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 17:00	
-	66	(bias with generator) same transistor same metal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 17:00	
-	1	(bias with generator) same transistor same metal same program$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/03 17:01	
-	2	365/230.06,201,226,190,203-205,194,154,156. and (bias with generator) same transistor same metal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/15 07:32	
-	12	program$4 with bias with test$4 and SRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/06 18:01	
-	3	((pull-up or pull-down) with transistor) same bias same test$4 and SRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 09:26	
-	6	((pull adj up) or (pull adj down) with transistor) same bias came test$4 and SRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/06 18:05	
-	16	(((pull-up or pull-down) with transistor) or (metal with program$4)) same (adjust$4 or level$) same bias same test$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 10:41	
-	17	("4916668" | "4967395" | "5132575" | "5245578" | "5302870" | "5369317" | "5555523" | "5677886" | "5680344" | "5701268" | "5732033" | "5862089" | "5877993" | "5912853" | "5991216" | "6052322" | "6157586").PN.	USPAT	2004/07/07 09:32	
-	4	6499081.URPN.	USPAT	2004/07/07 09:46	
-	3	(SRAM or (static with random with access with memory)) and adjust$ same magnitude$1 same bias same test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 09:51	
-	6	(SRAM or (static with random with access with memory)) and adjust$ same magnitude$1 same bias and test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 09:52	
-	35	365/230.06,201,226,190,203-205,194,154,156. and (SRAM or (static with random with access with memory)) and (adjust$ or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 and test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 10:20	

-	16	365/230.06,201,226,190,203-205,194,154,156 and (adjust$ or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 and test$3 and (SRAM or (static with random with access with	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:21
-	1	memory)) and (adjust$ or ((pull adj up) and (pull adj down) with transistor)) same (magnitude$1 with bias with voltage) and test$3 and (SRAM or (static with random with access with memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 10:06
-	2	365/230.06,201,226,190,203-205,194,154,156 and (SRAM or (static with random with access with memory)) and (adjust$ or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 and test$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 10:21
-	17	and ("4967380" | "5036460" | "5132575" | "5245578" | "5302870" | "5369317" | "5555523" | "5677886" | "5680344" | "5701268" | "5732033" | "5862089" | "5877993" | "5912853" | "5991216" | "6052322" | "6157586").PN.	USPAT	2004/07/07 10:32
-	14	(((pull-up or pull-down) with transistor) or (metal with program$4)) same (adjust$4 or level$) same bias same test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:01
-	2	(((pull-up or pull-down) with transistor) or (metal with program$4)) same (adjust$4 or level$) same bias same test$4 and (SRAM or (static with random with access memory)) and weak	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/07 12:09
-	14	(((pull-up or pull-down) with transistor) or (metal with program$4)) same (adjust$4 or level$) same bias same voltage same test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 10:12
-	4	(bias with generator) and (((pull-up or pull-down) with transistor) or (metal with program$4)) same (adjust$4 or level$) same bias same voltage same test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 10:13
-	96	365/$.ccls. and (((pull-up or pull-down) with transistor) or (metal with program$4)) and (adjust$4 or level$) and bias same voltage same test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:16
-	227	365/$.ccls. and (((pull-up or pull-down) with transistor) or (metal with program$4)) and (adjust$4 or level$) and (bias with voltage) and test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:17
-	16	365/$.ccls. and (((pull-up or pull-down) with transistor) or (metal with program$4)) and (adjust$4 or level$) and (bias with voltage with output with signal) and test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 10:41
-	35	365/230.06,201,226,190,203-205,194,154,156 and (adjust$ or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 and test$3 and (SRAM or (static with random with access with memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:24
-	11	(bias with generator) and SRAM and adjust$3 with magnitude	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 10:54

-	69	(((pull-up or pull-down) with transistor) or program$4) same (adjust$4 or chang$3) same bias same voltage$1 same test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 12:48
-	19	365/$.ccls. and (((pull-up or pull-down) with transistor) or program$4) same (adjust$4 or chang$3) same bias same voltage$1 same test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:10
-	21	365/$.ccls. and (((pull-up or pull-down) with transistor) or program$4) same (adjust$4 or chang$3 or modif$7) same bias same voltage$1 same test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:12
-	4	365/$.ccls. and (((pull-up or pull-down) with transistor) or program$4) same (adjust$4 or chang$3 or modif$7) same bias same voltage$1 same test$4 and (SRAM or (static adj random adj access adj memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:12
-	57	(program$4 and bias and test$4 and SRAM) aND (365/$.ccls. and (((pull-up or pull-down) with transistor) or (metal with program$4)) and (adjust$4 or level$) and (bias with voltage) and test$4 and (SRAM or (static adj random adj access adj memory)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:20
-	1	365/230.06,201,226,190,203-205,194,154,156. and (adjust$ OR CHANG$3 or modif$7 or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 same bias same voltage and test$3 and (SRAM or (static adj random adj access adj	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:23
-	34	365/230.06,201,226,190,203-205,194,154,156. and (adjust$ or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 and test$3 and (SRAM or (static adj random adj access adj	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:28
-	4	(program$4 and bias and test$4 and SRAM) aND (365/$.ccls. and (((pull-up or pull-down) with transistor) or (metal with program$4)) and (adjust$4 or level$) and (bias with voltage) and test$4 and (SRAM or (static adj random adj access memory)))) and (365/230.06,201,226,190,203-205,194,154,156.ccls. and (adjust$ or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 and test$3 and (SRAM or	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:24
-	69	365/230.06,201,226,190,203-205,194,154,156. and (adjust$ or chang$3 or modif$7 or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 and test$3 and (SRAM or (static adj random adj	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:29
-	1	365/230.06,201,226,190,203-205,194,154,156. and (adjust$ or chang$3 or modif$7 or ((pull adj up) and (pull adj down) with transistor)) same magnitude$1 same bias same voltage and test$3 and (SRAM or (static adj random adj access adj	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:30
-	3	(adjust$ or chang$3 or modif$7) same ((pull adj up) and (pull adj down) with transistor) same bias same voltage and (test$3 with (SRAM or (static adj random adj access adj memory)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 11:34
-	5	(((pull-up or pull-down) with transistor) or program$4) same (supply with voltage) same (bias with generator) same output and test$4 and (SRAM or (static with random with access memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/08 12:53